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1 Thermal resistance analysis by induced transient (TRAIT) method for power electronic devices thermal characterization. II. Practice and experiments

Bagnoli, P.E.; Casarosa, C.; Dallago, E.; Nardoni, M.;

Power Electronics, IEEE Transactions on , Volume: 13 , Issue: 6 , Nov. 1998
 Pages:1220 - 1228

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2 Thermal resistance analysis by induced transient (TRAIT) method for power electronic devices thermal characterization. I. Fundamentals and theory

Bagnoli, P.E.; Casarosa, C.; Ciampi, M.; Dallago, E.;

Power Electronics, IEEE Transactions on , Volume: 13 , Issue: 6 , Nov. 1998
 Pages:1208 - 1219

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Tanir, O.; Sevinc, S.;

Computer , Volume: 27 , Issue: 2 , Feb. 1994
 Pages:28 - 34

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King, R.J.;

Power Electronics, IEEE Transactions on , Volume: 4 , Issue: 4 , Oct. 1989
 Pages:434 - 441

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5 Adaptation of neural agent in dynamic environment: hybrid system genetic algorithm and neural network

Iba, T.; Takefuji, Y.;

Knowledge-Based Intelligent Electronic Systems, 1998. Proceedings KES '98. Second International Conference on , Volume: 3 , 21-23 April 1998

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6 A new CMOS readout circuit design for the IR FPA with adaptive gain control and current-mode background suppression

Chih-Cheng Hsieh; Chung-Yu Wu; Far-Wen Jih; Tai-Ping Sun; Horng Chang;

Circuits and Systems, 1996. ISCAS '96., 'Connecting the World', 1996 IEEE International Symposium on , Volume: 1 , 12-15 May 1996

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Tsai, K.; Ma, R.P.;

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